

Notice of References Cited

Application/Control No.

09/606,367

Applicant(s)/Patent Under

Reexamination

CHEN ET AL.

Examiner

Hiep Nguyen

Art Unit

2816

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,163,501	12-2000	Ohshima et al.	365/233
	B	US-6,239,624	05-2001	Yang et al.	327/55
	C	US-			
	D	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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